

<b>LIST OF ART CITED BY APPLICANT</b> <b>(PTO-1449)</b>			ATTY. DOCKET NO. <b>P-0776</b>		APPLN. SERIAL NO. <b>10/576,580</b>	
			APPLICANT(S) <b>Yoon-Seob EOM et al.</b>			
			FILING DATE <b>April 20, 2006</b>		GROUP <b>3744</b>	
<b>U.S. PATENT DOCUMENTS</b>						
EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE
	<b>3,811,293</b>	<b>05/1974</b>	<b>Flynn</b>			
	<b>6,272,878</b>	<b>08/2001</b>	<b>Chang</b>			
<b>U.S. PATENT APPLICATION PUBLICATIONS</b>						
	*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS	
	<b>2001/0035021</b>	<b>11/2001</b>	<b>Kang et al.</b>			
<b>U.S. PATENT APPLICATIONS</b>						
	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS	
<b>FOREIGN PATENT DOCUMENTS</b>						
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation
	<b>JP59-074439</b>	<b>04/1984</b>	<b>Japan (English Abstract &amp; full Japanese text)</b>			<input checked="" type="checkbox"/> Yes <input type="checkbox"/> No
	<b>JP10-068535</b>	<b>03/1998</b>	<b>Japan (English Abstract &amp; full Japanese text)</b>			<input checked="" type="checkbox"/> Yes <input type="checkbox"/> No
<b>OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)</b>						
EXAMINER			DATE CONSIDERED			

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.